



# SEMI Standards Staff Report

March 8, 2016

SEMI Japan

# SEMI Global 2016 Calendar of Events 1/2

Event Name	Event Details
ISS Europe 2016	Mar 6-8, 2016 Nice, France
FPD China 2016 SEMICON China 2016	March 15-17, 2016 Shanghai, China
LED Taiwan 2016	April 13-16, 2016 Taipei, Taiwan
SEMICON Southeast Asia	April 26-28, 2016 Penag, Malaysia
SEMI Advanced Semiconductor Manufacturing Conference (ASMC) 2016	May 16-19, 2016 Saratoga Spring, NY

# SEMI Global

## 2016 Calendar of Events 2/2

Event Name	Event Details
SEMICON Russia 2016	June 8-9, 2016 Moscow, Russia
SEMICON West 2016	July 12-14, 2016 San Francisco, California
SEMICON Taiwan 2016	September 7-9, 2016 Taipei, Taiwan
PV Taiwan 2016	October 12-14, 2016 Taipei, Taiwan
SEMICON Europa 2016	October 25-27, 2016 Grenoble, France
SEMICON Japan 2016	December 14-16, 2016 Tokyo, Japan

# Global Standards Meeting Schedule

<http://www.semi.org/en/standards-events>




- MAR 8, 2016  
Information & Control Japan TC Chapter Meeting  
Tokyo, Japan
- MAR 11, 2016  
Silicon Wafer Japan TC Chapter Meeting  
Tokyo, Japan
- MAR 15, 2016  
Photovoltaic China TC Chapter Spring Meeting  
Shanghai, China
- MAR 18, 2016  
Gases Japan TC Chapter/Facilities Japan TC Chapter  
Joint Meeting  
Tokyo, Japan
- MAR 23, 2016  
EHS Taiwan TC Chapter meeting  
Taipei, Taiwan
- APR 4-APR 7, 2016  
North America Standards Spring 2016 Meetings  
Milpitas and San Jose, California
- APR 6, 2016  
Flat Panel Display (FPD) - Materials & Components  
Japan TC Chapter Meeting  
Tokyo, Japan
- APR 14, 2016  
Physical Interfaces & Carriers Japan TC Chapter  
Meeting  
Tokyo, Japan
- APR 15, 2016  
3DS-IC Japan TC Chapter Meeting  
Tokyo, Japan
- APR 19, 2016  
EHS Japan TC Chapter Meeting  
Tokyo, Japan
- APR 22, 2016  
HB-LED China TC Chapter Spring Meeting  
Xuzhou, China
- APR 29, 2016  
Korea I&C TC Chapter meeting  
Seoul, Korea
- MAY 13, 2016  
Liquid Chemical Japan TC Chapter Meeting  
Tokyo, Japan
- June 10, 2016  
Assembly & Packaging Japan TC Chapter Meeting  
Tokyo, Japan

As of Mar. 8, 2016  
Please make sure most updated  
information in the above URL

# 2016 Critical Dates for SEMI Standards Ballots

Cycle	Ballot Submission Date	Voting Period Starts	Voting Period ends
Cycle 1	January 4	January 12	February 12
Cycle 2	February 2	February 16	March 17
Cycle 3	March 1	March 14	April 13
Cycle 4	April 15	April 26	May 26
Cycle 5	May 10	May 24	June 23
Cycle 6	July 22	July 29	August 28
Cycle 7	August 17	August 31	September 30
Cycle 8	October 17	October 24	November 23
Cycle 9	November 16	November 30	December 31

# A&R Ballot Review

A&R Cycle	Result	Notes
October 2015	 A&R_201510	All passed.
December 2015	 A&R_201512	<b>5816A failed.</b> Line item Revision to SEMI F30-0710, Start-Up and Verification of Purifier Performance Testing for Trace Gas Impurities and Particles at an Installation Site with title change to Test Method for the Start-Up and Verification of Purifier Performance Testing for Trace Gas Impurities and Particles at an Installation Site -> The reasons of reject votes are on the next slide.
February 2016	 A&R_201602	All passed.

# The reasons of 5816A rejected at A&R

1. 'Editorial' changes made to the Document title in response to Negatives 1 and 2 from Reject Voter 1 at the adjudication are not editorial. Although nature of those changes may have been regarded as the concomitant changes in conjunction with correction of non-conforming title in accordance with the special procedure defined in APPENDIX 4 of the PM, the special procedure does not justify implementing such changes of the Title during adjudication of the Ballot. Since PM APPENDIX 4 does not apply, the restriction of Title change in PM3.5.1 should be applied
2. Negative 3 and 4 from the Reject Voter 1 were to the outside of LI, and therefore should have been adjudicated as Not related, but the TC Chapter voted them as Related and Not persuasive.
3. 'Editorial' change to the Scope section in response to Negative 4 from the Reject Voter 1 is a technical change that is not concomitant to the title change. Any technical change to the Scope section is subject for major revision according to 3.5.1 of the procedure Manual unless such change is made as a concomitant change when TC corrects a non-conforming Title per PM Appendix4.

## SEMI Standards Publications (1/3)

Publication Cycle	New	Revised	Reapproved	Withdrawn
January 2016	6	7	0	0
February 2016	4	4	3	0

- Total SEMI Standards in portfolio: 960
  - Includes 115 Inactive Standards



# SEMI Standards Publications (2/3)

- New Standards

Cycle	Designation	Title	Committee	Region
January 2016	SEMI C89	Test Method for Particle Removal Performance of Liquid Filter Rated Below 30 nm with Inductively Coupled Plasma – Mass Spectroscopy (ICP-MS)	Liquid Chemicals	JA
January 2016	SEMI PV70	Test Method for In-Line Measurement of Saw Marks on Photovoltaic (PV) Silicon Wafers by Laser Triangulation Sensors	Photovoltaic	NA
January 2016	SEMI PV71	Test Method for In-Line, Noncontact Measurement of Thickness and Thickness Variation of Silicon Wafers for Photovoltaic (PV) Applications Using Laser Triangulation Sensors	Photovoltaic	NA
January 2016	SEMI D74	Guide for Measuring Dimensions of Plastic Films/Substrates	FPD - Materials & Components	JA
January 2016	SEMI G97	Specification for Adhesive Tray Used for Thin Chip Handling	Assembly & Packaging	JA
January 2016	SEMI M87	Test Method for Contactless Resistivity Measurement of Semi-Insulating Semiconductors	Compound Semiconductor	EU

# SEMI Standards Publications (3/3)

- New Standards

Cycle	Designation	Title	Committee	Region
February 2016	SEMI C92-0216	Test Method for Determining the Critical Pitting Temperature of Stainless Steel Surfaces Used in Corrosive Gas Systems by Use of a Ferric Chloride Solution	Gases	NA
February 2016	SEMI C93-0216 (Preliminary)	Guide for Determining the Quality of Ion Exchange Resin Used in Polish Applications of Ultrapure Water System	Liquid Chemicals	NA
February 2016	SEMI PV73-0216	Test Method for Thin-Film Silicon Photovoltaic (PV) Modules Light Soaking	Photovoltaic	CH
February 2016	SEMI PV74-0216	Test Method for the Measurement of Chlorine in Silicon by Ion Chromatography	Photovoltaic	CH

# Highlights from JRSC Meeting during SEMICON Japan 2015

- JRSC Chairs
  - Mitsuhiro Matsuda (Hitachi Kokusai Electrics) stepped down due to expiration of his term of office
  - Kenji Yamagata (Daifuku) was newly appointed, it was approved at the ISC meeting.
- TC Chapter Structure
  - Japan Chapter of Global Automated Test Equipment Technical Committee was disbanded

# PPT Template Update

- SEMI PPT template is updated.
  - The copyright for images of former Standards template was expired.
  - The new template was distributed to all the co-chairs and the TF leaders on March 2.
  - Please use the new one for any presentation materials and do not use or distribute with the former one.



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# Staff Contact Information from Jan. 1, 2016

Committee	Staff
Gases, Facilities, FPD M&C, FPD Meteorology, Liquid Chemical SIG: SEA, CGMG	<i>Naoko Tejima</i> <i>Manager, Standards &amp; EHS</i> <a href="mailto:ntejima@semi.org">ntejima@semi.org</a>
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JRSC, SPI TF, Compound, Micropatterning, Silicon Wafer, EHS, Automation Technology, Test, EHS SIG: ESG, SMG, EHS	<i>Junko Collins</i> <i>Director, Standards &amp; EHS</i> <a href="mailto:jcollins@semi.org">jcollins@semi.org</a>
Others	Staff
Standards Products General Information, SEMIViews	<i>C. Yanagisawa</i>
Other Standards Operation	<i>J. Collins</i>

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# Backup

# SEMI Standards Publications

## Inactive Standards

Committee	Number of Inactive Standards
Assembly & Packaging	24
Automated Test Equipment	2
Compound Semiconductor Materials	4
Environmental Health & Safety	2
Facilities	8
FPD – Equipment	5
FPD – Materials & Components	5
FPD – Substrate	1



# SEMI Standards Publications

## Inactive Standards Cont.

Committee	Number of Inactive Standards
Gases	3
Information & Control	29
Liquid Chemicals	6
MEMS	1
Metrics	4
Micropatterning	10
Physical Interfaces & Carriers	3
Silicon Wafer	4
Traceability	2